## OP508F, OP509 Series



#### Features:

- Flat lensed for wide acceptance angle (OP508F)
- Lensed for high sensitivity (OP509)
- Easily stackable on 0.100" (2.54 mm) hole centers
- Inexpensive plastic package
- Mechanically and spectrally matched to OP168 and OP268 series of infrared emitting diodes



#### **Description:**

Each device in the **OP508F** series consists of a NPN silicon phototransistor mounted in a flat, black plastic "end-looking" package. The flat sensing surface allows an acceptance half-angle of 60° when measured from the optical axis to the half power point.

Each device in the **OP509** series consists of a NPN silicon phototransistor mounted in a lensed, clear plastic "end-looking" package. The lensing effect of the package allows an acceptance half-angle of 25° when measured from the optical axis to the half power point.

**OP508F** and **OP509** series devices can be mounted on 0.100" (2.54 mm) hole centers, which makes them an ideal low-cost alternate to hermetic OP600 sensors. **OP508F** and **OP509** series devices are mechanically and spectrally matched to the OP168F and OP268F series of infrared emitting diodes.

Please refer to Application Bulletins 208 and 210 for additional design information and reliability (degradation) data.

For custom versions of the OP508F, OP509 and OP538F series devices please contact your OPTEK representative.

### **Applications:**

- Applications requiring a wide acceptance angle
- · Applications requiring high sensitivity
- Space-limited applications

Ordering Information					
Part Number	Sensor	Viewing Angle	Lead Length		
OP508FA		120°			
OP508FC		120			
OP509A	Phototransistor		0.50"		
OP509B		50°			
OP509C					

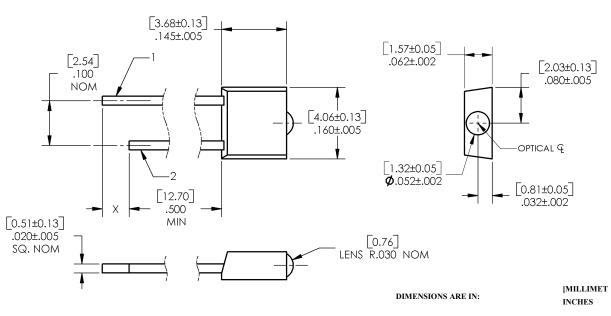


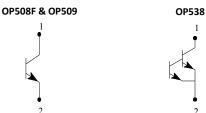
OP508F, OP509 Series



#### **OP508F (A, C)** [3.24±0.05] .128±.002 [1.52±0.13] EMITTING SURFACE [2.54] .060±.005 [2.03±0.25] .100 NOM .080±.01 [4.06±0.13] .160±.005 OPTICAL Q [0.76±0.13] Χ .030±.005 [12.70] [0.51±0.13] .500 .020±.005 SQ. NOM MIN MILLIM DIMENSIONS ARE IN: INCHES

### OP509 (A, B)





Pin#	Transistor	
1	Collector	
2	Emitter	

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### **Electrical Specifications**

Absolute Maximum Ratings (T <sub>A</sub> = 25° C unless otherwise noted)			
Storage and Operating Temperature Range	-40° C to +100° C		
Collector-Emitter Voltage	30 V		
Emitter-Collector Voltage	5 V		
Lead Soldering Temperature [1/16 inch (1.6 mm) from case for 5 seconds with soldering iron]	260° C <sup>(1)</sup>		
Power Dissipation	100 mW <sup>(2)</sup>		

Electrical Characteristics (T <sub>A</sub> = 25° C unless otherwise noted)						
SYMBOL	PARAMETER	MIN	TYP	MAX	UNITS	TEST CONDITIONS
I <sub>C(ON)</sub>	On-State Collector Current OP509A (Dome Lens) OP508FA (Flat Lens) OP509B (Dome Lens) OP508FC (Flat Lens)	5.70 2.70 1.40 0.34	- - -	20.00 - 10.60 -	mA	$V_{CE} = 5.0 \text{ V}, E_E = 5 \text{ mW/cm}^{2(3)}$
I <sub>C</sub> /Δ T	Relative I <sub>C</sub> Charge with Temperature	-	1.00	-	%/°C	$V_{CE} = 5 \text{ V.0, } E_E = 1.0 \text{ mW/cm}^{2(3)}, \lambda = 890 \text{ nm}$
I <sub>CEO</sub>	Collector-Dark Current OP508F & OP509 OP538F	-	- -	100 225	nA	V <sub>CE</sub> = 10.0 V, E <sub>E</sub> = 0 <sup>(4)</sup>
V <sub>(BR)CEO</sub>	Collector-Emitter Breakdown Voltage OP508F & OP509	30	-	-	V	I <sub>C</sub> = 1.00 mA, E <sub>E</sub> = 0
$V_{(BR)ECO}$	Emitter-Collector Breakdown Voltage	5	-	-	V	Ι <sub>Ε</sub> = 100 μΑ
V <sub>CE(SAT)</sub>	Collector-Emitter Saturation Voltage  OP508F  OP509	-	-	0.4	V	$I_C$ = 300 μA, $E_E$ = 5 mW/cm <sup>2 (3)</sup> $I_C$ = 250 μA, $E_E$ = 5 mW/cm <sup>2 (3)</sup>

#### Notes:

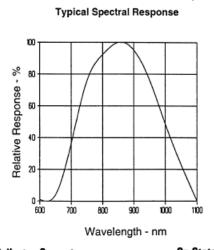
- 1. RMA flux is recommended. Duration can be extended to 10 seconds maximum when flow soldering. A maximum 20 grams force may be applied to the leads when soldering.
- 2. Derate linearly 1.33 mW/° C above 25° C.
- 3. Light source is an unfiltered GaAs or GaAlAs LED with a peak emission wavelength of 935 or 890 nm and a radiometric intensity level which varies less than 10% over the entire lens surface of the phototransistor being tested.
- 4. To calculate typical collector dark current in  $\mu A$ , use the formula  $I_{CEO}=10^{(0.040\,\text{T}_A-3.4)}$ , where  $T_A$  is ambient temperature in °C.

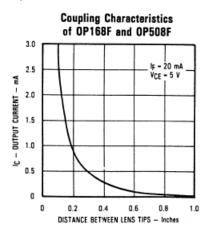
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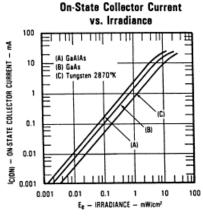
### **Performance**

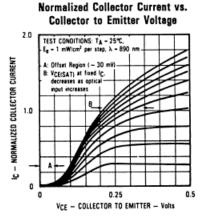
### OP508FA, OP508FC, OP508FD

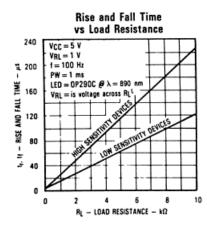


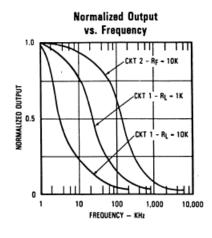


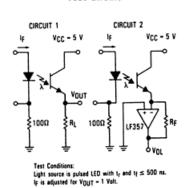
**Normalized Collector Current** vs. Angular Displacement 1.1 0.9 NORMALIZED COLLECTOR CURRENT 0.7 0.5 TEST CONDITIONS: 0.3 λ - 890 nm VCE = 5 V LENS TO LENS 0.1 0 0 30 30 90 60  $\theta$  - ANGULAR DISPLACEMENT - Deg.











**Switching Time** 

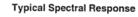
**Test Circuit** 

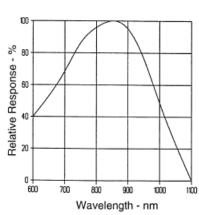
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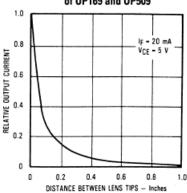
### **Performance**

OP509A, OP509B, OP509D

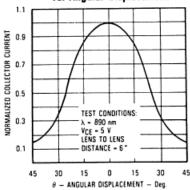




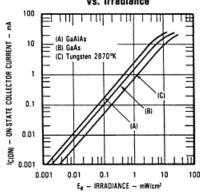
#### Coupling Characteristics of OP169 and OP509



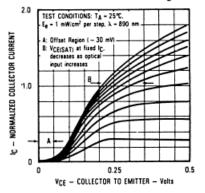
# Normalized Collector Current vs. Angular Displacement



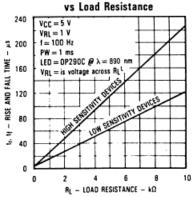
# On-State Collector Current vs. Irradiance



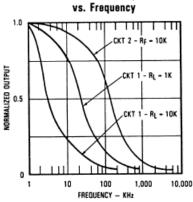
#### Normalized Collector Current vs. Collector to Emitter Voltage



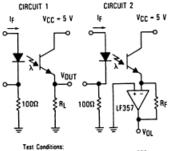
## Rise and Fall Time



## Normalized Output



### Switching Time Test Circuit



Test Conditions: Light source is pulsed LED with  $t_i$  and  $t_i \le 500$  n:  $t_i$  is adjusted for  $V_{OUT} = 1$  Volt.

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Issue	Change Description	Approval	Date
	Used PDFs from PDF Catalog to write new data sheet.		June 1996
А	Wrote data sheet using above PDFs and information from some unreleased Publisher files (see USED folder).		04/04/06
	Transferred to new TT Electronics template.		8/2016